

TEST SPECIFICATION



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COMMUNICATION PROTOCOL

FSK Physical Layer Test Specification

HCF_TEST-002, FCG TT20002
Revision 3.0

Release Date: 23 February 2024

Release Date: 23 February 2024

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Use of imperatives in HART Specifications

The key words (imperatives) "must", "required", "shall", "should", "recommended", "may", and "optional" when used in this document are to be interpreted as follows:

- | | |
|---------------|--|
| Must | Must, Shall, or Required denotes an absolute mandatory requirement. For example, "All HART Field Devices must implement all Universal Commands" |
| Should | Should or Recommended indicates a requirement that, given good cause/reason, can be ignored. However, the consequences of ignoring the requirement must be fully understood and well justified before doing so. |
| May | May or Optional identifies a requirement that is completely optional and can be supported at the discretion of the implementation. May can be used to identify optional Application functionality and, when this is the case, does not imply the function is optional in Field Devices. |

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Table of Contents

Preface	5
Introduction.....	6
1. Scope.....	7
2. References.....	7
2.1 The HART-Field Communications Protocol Specifications	7
2.2 Other FieldComm Group Documents	7
3. Definitions	8
4. Symbols and Abbreviations	13
5. Test Procedures	13
6. Test Configurations	14
7. Test Substitutions	14
8. Test Conditions.....	14
9. Test Results.....	15
10.Physical Layer Test Equipment	15
10.1 Test Load Resistor Properties	15
10.2 Oscilloscope.....	15
10.3 Frequency counter	15
10.4 DC Power Source.....	16
10.5 PC and Software	16
10.6 PhL Test Interface	16
10.7 High Impedance Current Source	16
10.8 Test Filters.....	16
10.9 RMS Digital Voltmeter (DVM).....	16
10.10 Signal Generator	17
10.11 AC Ammeter.....	17
11.Physical Device Types	18
12.Device Test Setup	20
12.1 General Test Setup for Transmitter, Actuator, Non-DC Isolated Bus Device	20
12.2 General Test Setup for Secondary, Current Output, DC Isolated Bus Device, Voltage Output, Maintenance Port.....	20
12.3 General Test Setup for Current Input, Voltage Input	21
13.Physical Layer Tests	22
13.1 Waveshape	23
13.2 Carrier Start/Stop/Decay Timing	28
13.3 Carrier Transient	31
13.4 Output Noise During Silence	36
13.5 Analog Rate of Change	39
13.6 Receive Impedance Measurement	42
13.7 Send Impedance Measurement	50
13.8 Noise Sensitivity Tests	54
13.9 Carrier Detect Tests.....	57

ANNEX A. Test Circuits	61
A.1 Simulated Sensor Circuit Suitable for Analog Rate of Change Test.....	61
A.2 HCF Tools - Filter Characteristics	62
ANNEX B. Bipolar Power Supplies	63
ANNEX C. Revision History.....	64
C.1 Changes from Revision 2.2 to 3.0	64
C.2 Changes from Revision 2.1 to 2.2	64
C.3 Changes from Revision 2.0 to 2.1	64
C.4 Changes from Revision 1.1 to 2.0	65